

CITATION  
 MAY 17 2002  
 S. PATES  
 TRADEMARK

Doctor's Name (Printed)

TSMC-01-144

Application Number

10/086,258

~~Significant~~

Ming-Hwa Yoo et al.

Filing Date

03/04/02

Group 11 Unit

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U. S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

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OTHER DOCUMENTS (Including Author, Title, Date, Portion of Pages, Etc.)

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FORM PTQ-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMEX.291A	APPLICATION NO. 10/074,563
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Todd et al.	
		FILING DATE February 11, 2002	GROUP 1762



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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
						YES	NO	
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	H3-187215	8/15/91	Japan (Patent Disclosure)			X		
	H3-91239	4/16/91	Japan (Patent Disclosure)			X		
	H5-62911	3/12/93	Japan (Patent Disclosure)			X		

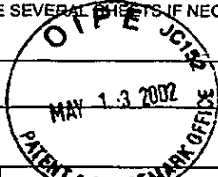
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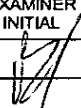

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
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10/074,583INFORMATION DISCLOSURE STATEMENT  
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